

200351953

Docket No. I431.144.101/FIN 503 PCT/US  
ELECTRICAL CIRCUIT AND METHOD FOR TESTING  
ELECTRONIC COMPONENT  
Claus Dworski et al.  
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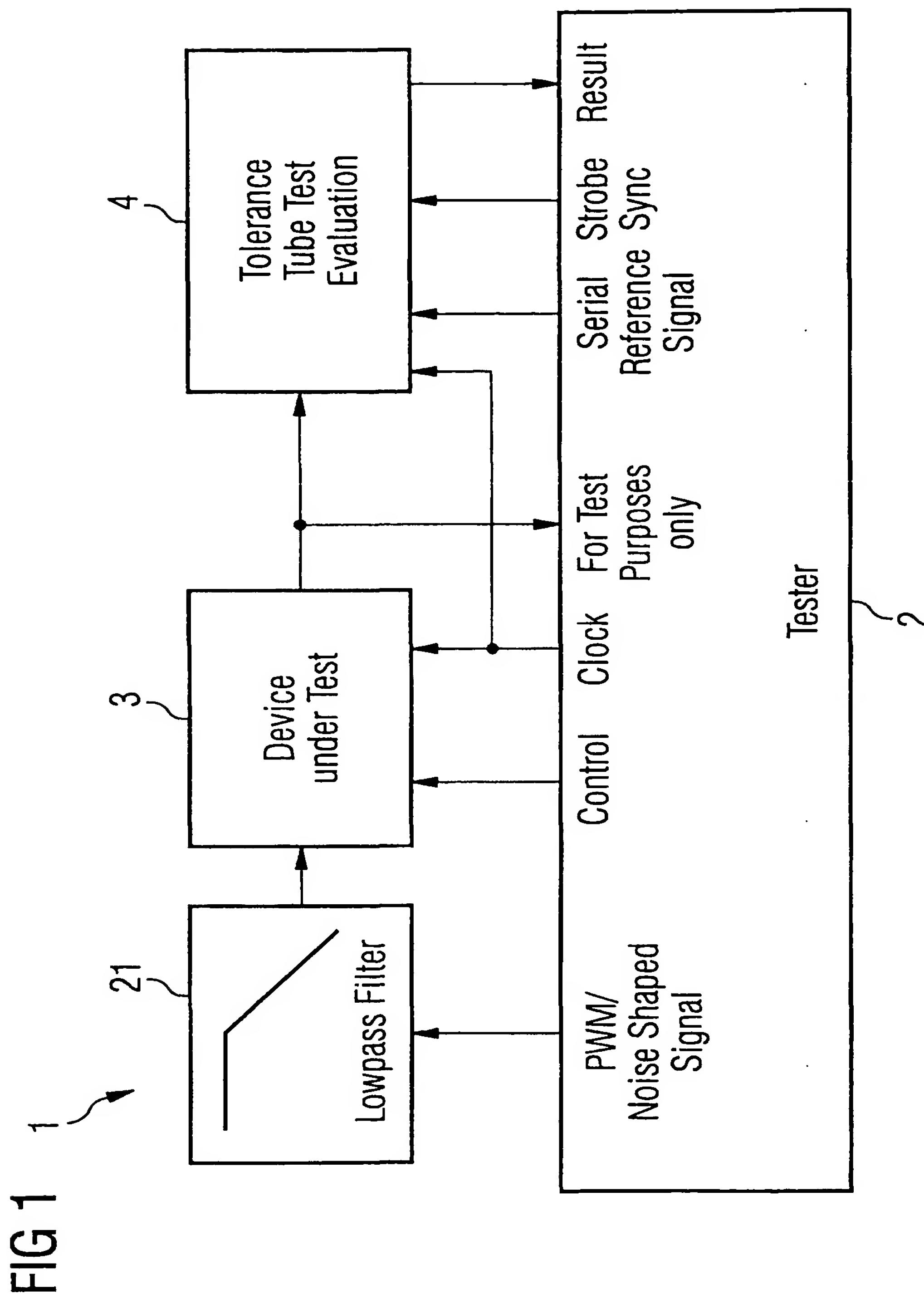
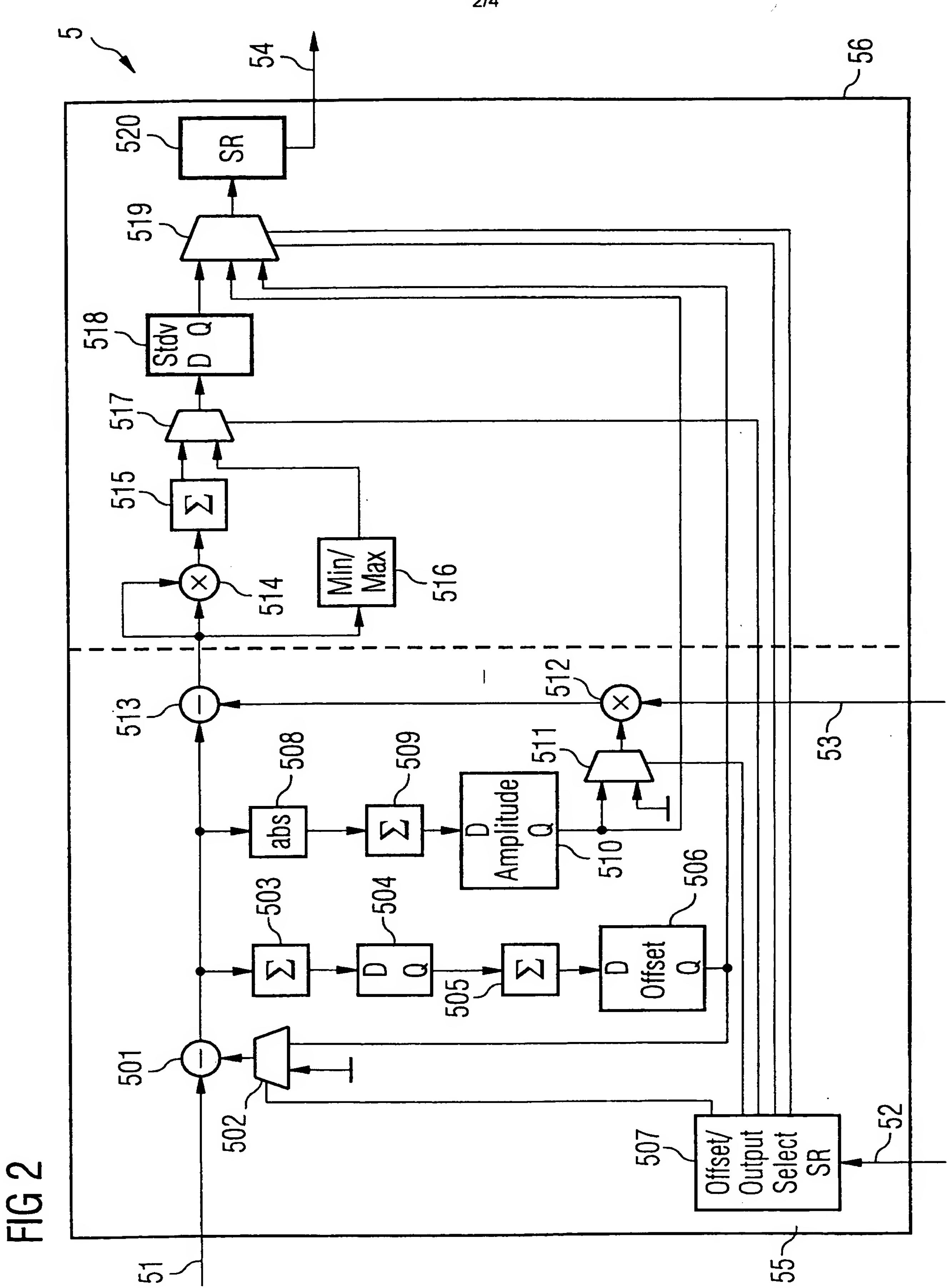


FIG 1

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FIG 3

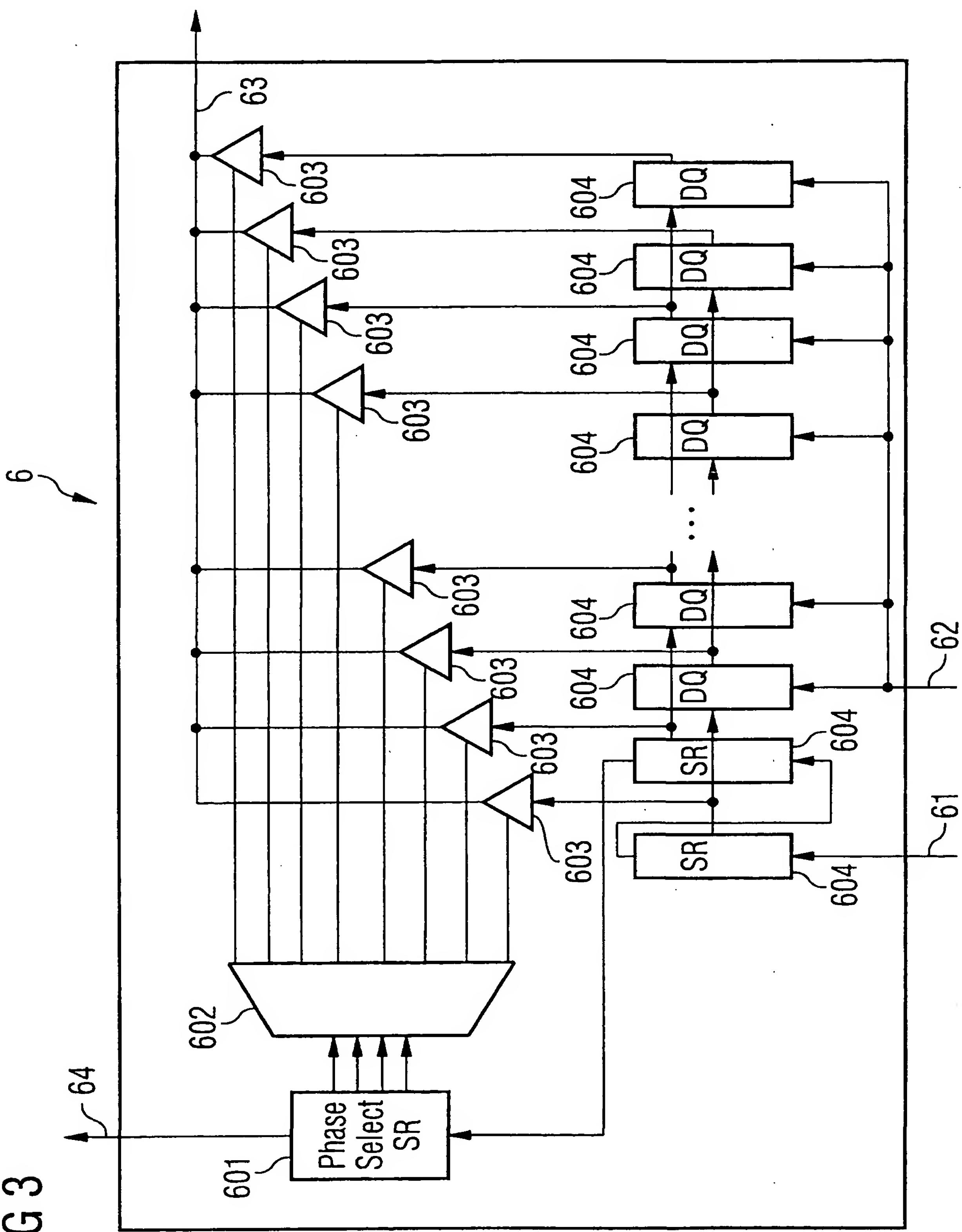
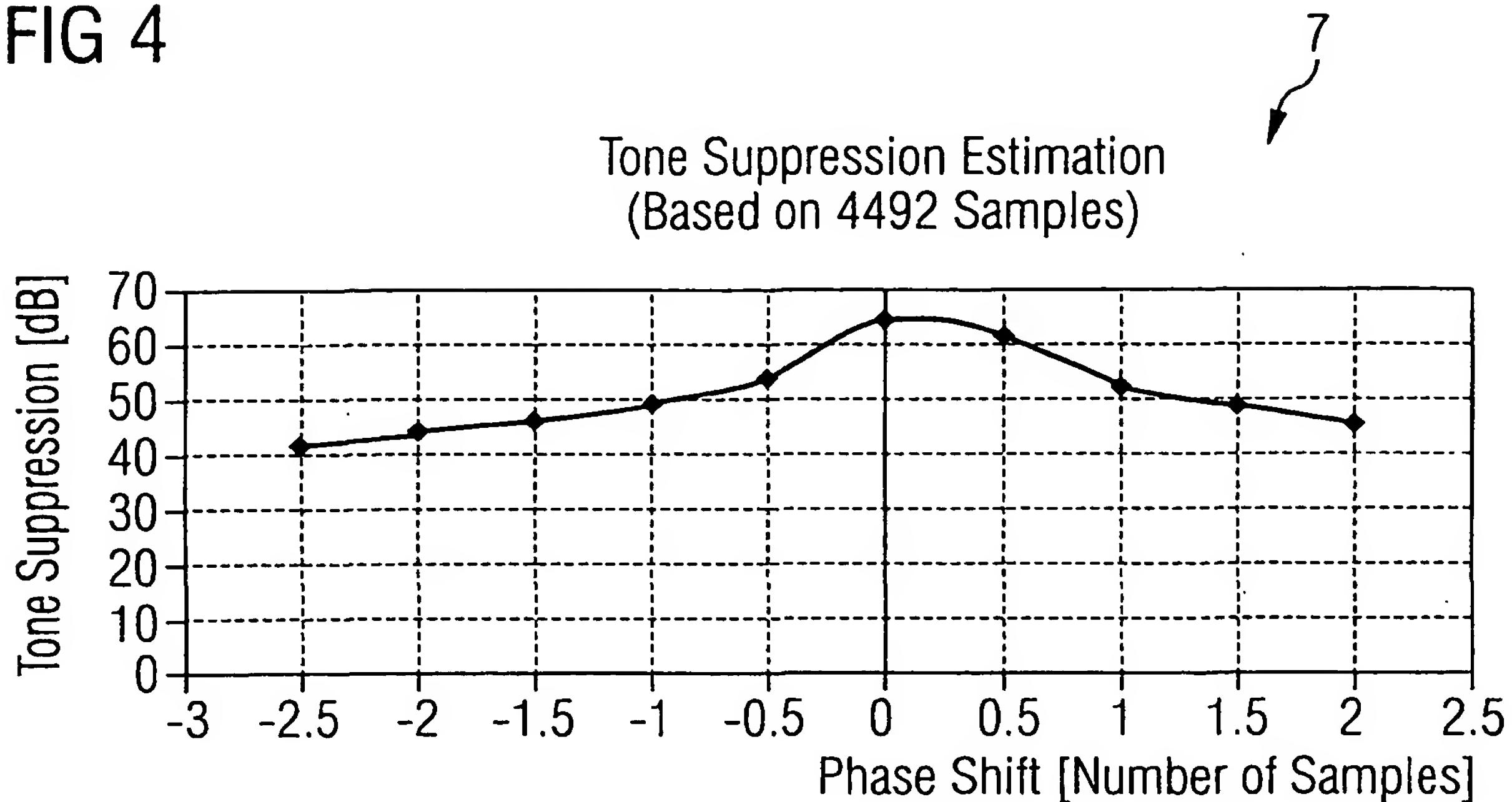


FIG 4



Phase Shift [Number of Samples]	-2.5	-2	-1.5	-1	-0.5	0	0.5	1	1.5	2
Tone Suppression [dB]	42.4	44.2	46.4	49.4	54	64.6	61.8	53.1	48.8	46